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| Notice of References Cited | Application/Control No. 10/575,449 | | Applicant(s)/Patent Under Reexamination ROYERE ET AL. | |
| | Examiner Kevin S. Orwig | | Art Unit 1611 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-5,948,855 A | 09-1999 | Lin et al. | 524/837 |
| * | B | US-5,980,936 A | 11-1999 | Krafft et al. | 424/450 |
| * | C | US-6,627,603 B1 | 09-2003 | Bibette et al. | 514/3 |
| * | D | US-2004/0137019 A1 | 07-2004 | Nakamura et al. | 424/401 |
| * | E | US-6,866,838 B1 | 03-2005 | Mondain-Monval et al. | 424/9.52 |
| * | F | US-7,214,717 B1 | 05-2007 | Jaques Bibette et al. | 516/54 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|-----------------|-----------------|----------------|
| | N | WO 01/21297 | 03-2001 | World Intellect | Bibette et al. | B01F 17/00 |
| | O | WO 99/07463 | 02-1999 | World Intellect | Bibette et al. | B01F 17/00 |
| | P | WO 02/074260 | 09-2002 | World Intellect | Nakamura et al. | A61K 7/00 |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

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